L Number	Hits	Search Text	DB	Time stamp
1	0	(5404358.pn.) and chain	USPAT; US-PGPUB;	2004/04/13
2	1	(5404358.pn.) and serial\$2	EPO; JPO; DERWENT; IBM_TDB USPAT;	2004/04/13
		(ololootpiii) ulia bollalt	US-PGPUB; EPO; JPO; DERWENT; IBM TDB	14:02
3	1	(5404358.pn.) and serial\$2 and switch\$3	USPĀT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 14:14
4	5	(second adj scan adj register\$1) and chain\$1	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/13 14:39
5	35	scan adj register\$1 adj chain\$1	USPĀT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:05
6	1	(scan adj register\$1 adj chain\$1) with bypass\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:20
7	93	(scan adj chain\$1) with bypass\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:21
8	36	(scan adj chain\$1) with register with bypass\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 16:25
9	0	(scan adj chain\$1) with bypass\$3 with switch\$3	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/13 15:26
10	3	(scan with chain\$1) with bypass\$3 with switch\$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/13 15:27
11	2	((scan with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/13 15:28
12	4	((register with chain\$1) with bypass\$3 with switch\$3) and (semiconductor or IC)	USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 15:29
13	2	5491666.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT;	2004/04/13 17:39
14	3	6708304.pn.	IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2004/04/13 17:39

Search History

_	2	20020144200.pn.	USPAT;	2004/04/05
			US-PGPUB;	15:46
			EPO; JPO;	
		·	DERWENT;	
	0	(714/726.pn.) and scan\$4 and test\$3 and	IBM_TDB USPAT;	2004/04/05
-	0	(semiconductor\$1 or (integrated adj	US-PGPUB;	15:50
Ì		circuit\$1) or IC) and analog and	EPO; JPO;	13.30
		(internal adj circuit) and pin\$1 and	DERWENT;	
		(scan adj register\$1) and (input adj	IBM TDB	
		output)	_	
-	13	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/05
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	15:59
		analog and (internal adj circuit) and	EPO; JPO;	
		pin\$1 and (scan adj register\$1) and	DERWENT; IBM TDB	
1	4	<pre>(input adj output) scan\$4 and test\$3 and (semiconductor\$1 or</pre>	USPAT;	2004/04/08
-	"	(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:00
		analog and (internal adj circuit) and	EPO; JPO;	
	}	pin\$1 and (scan adj register\$1) and	DERWENT;	
		(input adj output) and (short with	IBM_TDB	
		wiring)		
-	2	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:01
1		analog and (internal adj circuit) and pin\$1 and (scan adj register\$1) and	EPO; JPO; DERWENT;	
		final and (Scan ad) registeral) and (input adj output) and (analog with	IBM TDB	
		(input adj odeput) and (analog with		
_	6	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:06
		analog and (internal adj circuit) and	EPO; JPO;	
		pin\$1 and (scan adj register\$1) and	DERWENT;	
		(input adj output) and (analog with	IBM_TDB	
	2	input) scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
-		(integrated adj circuit\$1) or IC) and	US-PGPUB;	11:07
		(internal adj circuit) and pin\$1 and	EPO; JPO;	
		(scan adj register\$1) and (input adj	DERWENT;	
		output) and (analog with pin\$1)	IBM_TDB	
_	32	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	16:35
		pin\$1 and (scan adj register\$1) and	EPO; JPO; DERWENT;	
		(input adj output) and (analog with pin\$1)	IBM TDB	
_	22	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:28
		pin\$1 and (scan adj register\$1) and	EPO; JPO;	
	1	(input adj output) and (analog with	DERWENT;	
	_	pin\$1) and (JTAG with scan\$4)	IBM_TDB	2004/04/00
-	2	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT; US-PGPUB;	2004/04/08 14:56
		(integrated adj circuit\$1) or IC) and pin\$1 and ((scan adj register\$1) with	EPO; JPO;	11.70
		((input adj output) adj pin)) and (analog	DERWENT;	
		with pin\$1)	IBM TDB	
-	2		USPĀT;	2004/04/08
			US-PGPUB;	15:58
	1		EPO; JPO;	
	1		DERWENT;	
_	0	JP05322989.pn.	USPAT;	2004/04/08
-		0 E 0 3 3 2 2 3 0 3 . p. 1.	US-PGPUB;	15:59
	1		EPO; JPO;	
	1		DERWENT;	
	1		IBM_TDB	
-	0	JP5322989.pn.	USPAT;	2004/04/08
			US-PGPUB;	15:59
			EPO; JPO; DERWENT;	
			IBM TDB	
	L		1 7 7 1 1 1 1 1	l

_	1	05322989.pn.	USPAT;	2004/04/08
			US-PGPUB;	16:01
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
_	112834	TORU.INV.	USPAT;	2004/04/08
			US-PGPUB;	16:02
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	112834	TORU.IN.	USPAT;	2004/04/08
			US-PGPUB;	16:02
			EPO; JPO;	
		·	DERWENT;	
			IBM_TDB	
-	0	TORU-SHIONO.IN.	USPAT;	2004/04/08
			US-PGPUB;	16:03
			EPO; JPO;	
			DERWENT;	
	_		IBM_TDB]
-	2	TORU-SH\$4.IN.	USPAT;	2004/04/08
			US-PGPUB;	16:03
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	0004/04/00
_	0	TORU-SHIONO.IN.	USPAT;	2004/04/08
			US-PGPUB;	16:06
			EPO; JPO;	
			DERWENT;	
		11020001 BY	IBM_TDB	2004/04/00
-	2	11038091.PN.	USPAT;	2004/04/08
			US-PGPUB;	16:06
			EPO; JPO;	
			DERWENT;	
	2	20020144200.pn.	IBM_TDB USPAT;	2004/04/08
-		20020144200.pm.	US-PGPUB;	16:36
			EPO; JPO;	10.30
			DERWENT;	
			IBM TDB	
_	144	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
	144	(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:29
		(scan adj register\$1) and (JTAG with	EPO; JPO;	
		scan\$4 with register)	DERWENT;	
		Tourist Togetoot/	IBM TDB	
_	41	scan\$4 and test\$3 and (semiconductor\$1 or	_	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:30
	1	(scan adj register\$1) and (JTAG with	EPO; JPO;	
	1	scan\$4 with register) and (JTAG with	DERWENT;	
	1	specification)	IBM TDB	
-	9	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
		(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:35
		(scan adj register\$1) and (JTAG with	EPO; JPO;	
		scan\$4 with register) and (JTAG with	DERWENT;	
		specification) and (register with chain)	IBM TDB	ĺ
		and (control\$3 with (scan adj register))		
	1	scan\$4 and test\$3 and (semiconductor\$1 or	USPAT;	2004/04/08
	_	(integrated adj circuit\$1) or IC) and	US-PGPUB;	17:35
		(scan adj register\$1) and (JTAG adj	EPO; JPO;	
		(scan\$4 adj register)) and (JTAG with	DERWENT;	
		specification) and (register with chain)	IBM_TDB	
	L	and (control\$3 with (scan adj register))		